

LABORATORY REPORT

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Report No.: 10100547-002-v1
Date Received: 10/15/2010
Date Reported: 11/4/2010
P.O. No.: Verbal VB

Portsmouth, NH 13801

Sample Description: Implant with an abutment attached

Background

A dental implant identified as Implant 4.3 x 12, #0014312, Lot A-1984 and an abutment identified as Prepable Abutment 4.6 x 6.5, #002062, Lot #00054 were submitted for examination. The abutment was inserted into the implant and tightened using a 20 Ncm non-adjustable torque wrench supplied by the client. The implant with the attached abutment was then mounted and polished per standard metallographic procedures. See Figure 1.


Results

The implant was then examined with a Scanning Electron Microscope (SEM) equipped with an X-ray Energy Dispersive Spectrographic Microprobe (EDS) at magnifications up to 4000X. The SEM photomicrographs taken to document the implant/abutment interface are shown in Figures 2 and 3.

Conclusion

The dental implant and abutment were in intimate contact (no gap was detected) in continuous areas along the interface length.

Note: The material will be discarded after sixty (60) days from the date of this report unless otherwise directed.

Approved By: 
W. Don Bunn, PE
Project Engineer

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Figure 1, Cross section of the implant with the abutment inserted at 10X magnification

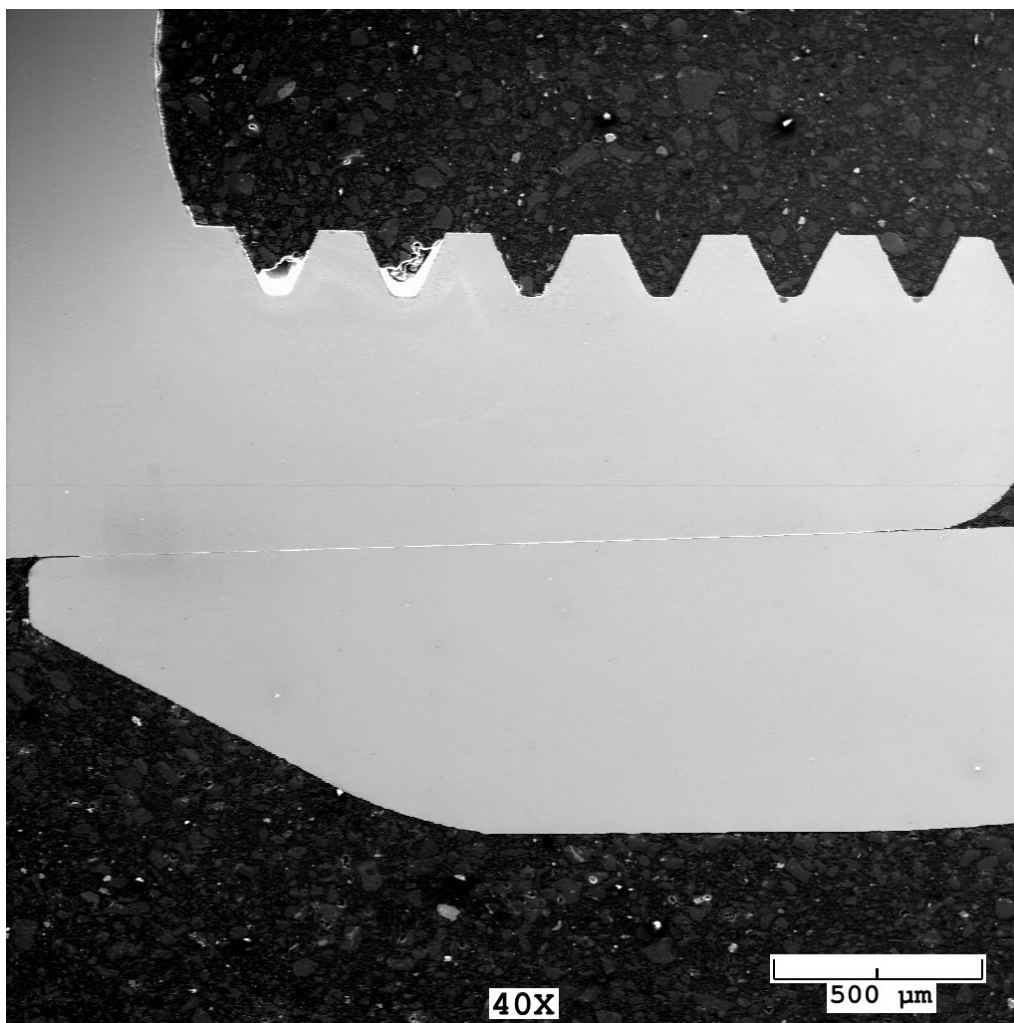


Figure 2, Implant / abutment interface as viewed with a SEM at 40X magnification

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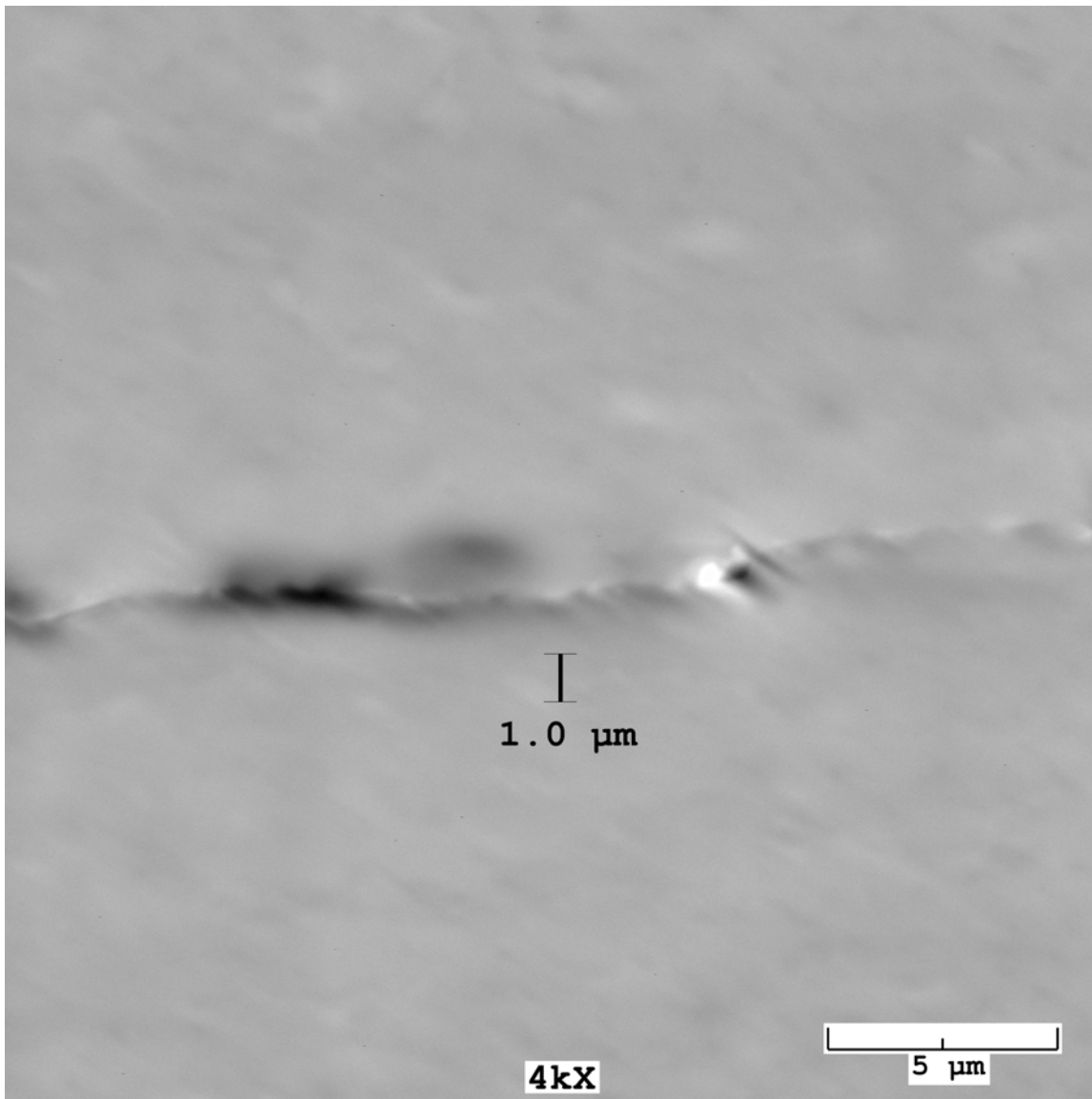


Figure 3, A section of the Implant / abutment interface as viewed with a SEM at 4000X magnification. The dark areas are discolorations from the polishing process.